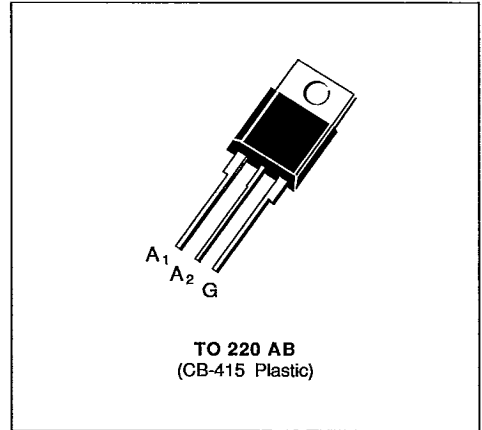


- $I_{TRMS} = 8\text{ A}$ at $T_c = 90\text{ °C}$.
- $V_{DRM} : 200\text{ V}$ to 800 V .
- $I_{GT} = 35\text{ mA}$ (QI-II-III).
- GLASS PASSIVATED CHIP.
- HIGH SURGE CURRENT : $I_{TSM} = 80\text{ A}$.
- HIGH COMMUTATION CAPABILITY :
(di/dt)_c > 4.5 A/ms without snubber.
- INSULATING VOLTAGE : 2500 V_{RMS} .

**DESCRIPTION**

New range suited for applications such as phase control and static switching on inductive or resistive load.

ABSOLUTE RATINGS (limiting values)

Symbol	Parameter		Value	Unit
I_{TRMS}	RMS on-state current (360 ° conduction angle)	$T_c = 90\text{ °C}$	8	A
I_{TSM}	Non repetitive surge peak on-state current (T_j initial = 25 °C)	$t = 8.3\text{ ms}$	85	A
		$t = 10\text{ ms}$	80	
I^2t	I^2t value	$t = 10\text{ ms}$	32	A^2s
di/dt	Critical rate of rise of on-state current (1)	Repetitive $F = 50\text{ Hz}$	20	$A/\mu s$
		Non Repetitive	100	
T_{Jstg} T_j	Storage and operating junction temperature range		- 40, + 150 - 40, + 125	$^{\circ}C$ $^{\circ}C$

Symbol	Parameter	BTA 08-					Unit
		200 CW	400 CW	600 CW	700 CW	800 CW	
V_{DRM}	Repetitive peak off-state voltage (2)	± 200	± 400	± 600	± 700	± 800	V

(1) Gate supply : $I_G = 350\text{ mA}$ -- $dc/dt = 1\text{ A}/\mu s$.
(2) $T_j = 125\text{ °C}$.

THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
$R_{th(j-a)}$	Junction to ambient	60	°C/W
$R_{th(j-c)}^{DC}$	Junction to case for DC	4.3	°C/W
$R_{th(j-c)}^{AC}$	Junction to case for 360 ° conduction angle (F = 50 Hz)	3.2	°C/W

GATE CHARACTERISTICS (maximum values)

$P_{GM} = 40 \text{ W}$ (t = 10 μs) $P_{G(AV)} = 1 \text{ W}$ $I_{GM} = 4 \text{ A}$ (t = 10 μs) $V_{GM} = 16 \text{ V}$ (t = 10 μs).

ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions	Quadrants	Min.	Typ.	Max.	Unit	
I_{GT}	$T_j = 25 \text{ °C}$ $V_D = 12 \text{ V}$ $R_L = 33 \text{ }\Omega$ Pulse duration > 20 μs	I-II-III	1		35	mA	
V_{GT}	$T_j = 25 \text{ °C}$ $V_D = 12 \text{ V}$ Pulse duration > 20 μs	I-II-III			1.5	V	
V_{GD}	$T_j = 125 \text{ °C}$ $V_D = V_{DRM}$ Pulse duration > 20 μs	I-II-III	0.2			V	
I_H^*	$T_j = 25 \text{ °C}$ $I_T = 100 \text{ mA}$ Gate open $R_L = 140 \text{ }\Omega$				35	mA	
I_L	$T_j = 25 \text{ °C}$ $V_D = 12 \text{ V}$ Pulse duration > 20 μs	I-III			50	mA	
		II			80		
V_{TM}^*	$T_j = 25 \text{ °C}$ $I_{TM} = 11 \text{ A}$ $t_p = 10 \text{ ms}$				1.75	V	
I_{DRM}^*	$T_j = 25 \text{ °C}$ $T_j = 125 \text{ °C}$	V_{DRM} rated	Gate open			0.01	mA
						2	
dv/dt^*	$T_j = 125 \text{ °C}$ Gate open Linear slope up to 0.67 V_{DRM}		250	500		V/ μs	
$(di/dt)_c^*$	$T_j = 125 \text{ °C}$ V_{DRM} rated Without snubber		4.5	9		A/ms	
t_{gt}	$T_j = 25 \text{ °C}$ $di_G/dt = 1 \text{ A}/\mu\text{s}$ $I_T = 11 \text{ A}$ $V_D = V_{DRM}$	I-II-III		2		μs	

* For either polarity of electrode A₂ voltage with reference to electrode A₁.

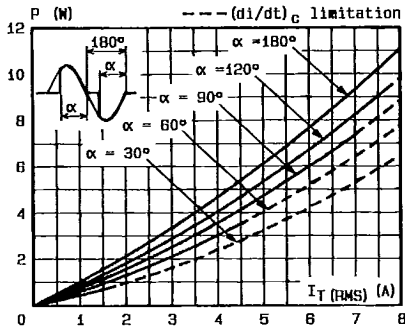


Fig. 1 - Maximum mean power dissipation versus RMS on-state current (F = 60 Hz).

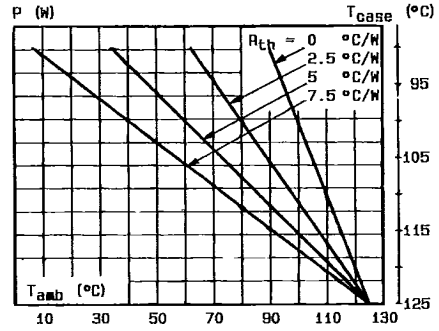


Fig. 2 - Correlation between maximum mean power dissipation and maximum allowable temperatures (T_amb and T_case) for different thermal resistances heatsink + contact.

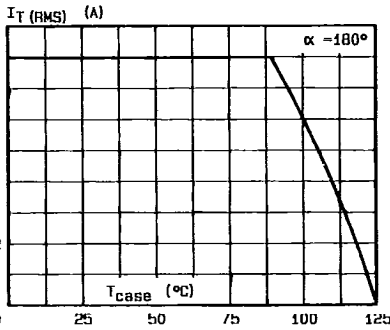


Fig. 3 - RMS on-state current versus case temperature.

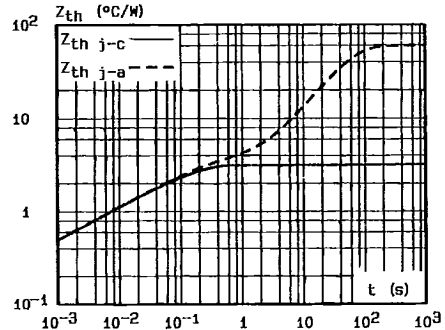


Fig. 4 - Thermal transient impedance junction to case and junction to ambient versus pulse duration.

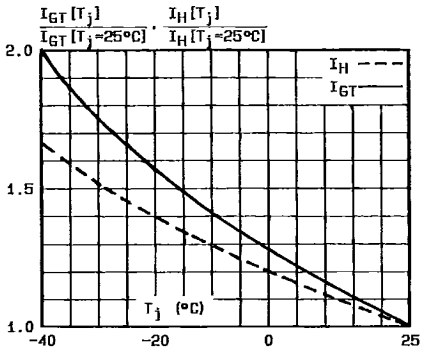


Fig. 5 - Relative variation of gate trigger current and holding current versus junction temperature.

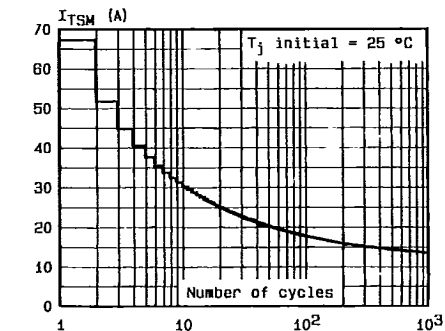


Fig. 6 - Non repetitive surge peak on-state current versus number of cycles.

